

Notice of References Cited	Application/Control No. 10/509,461		Applicant(s)/Patent Under Reexamination VAN DEN OETELAAR ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,726,970 A	03-1998	Kaneko et al.	369/275.2
*	B	US-6,067,312 A	05-2000	Matz et al.	372/96
*	C	US-2001/0016242 A1	08-2001	Miyamoto et al.	428/64.4
*	D	US-2004/0043254 A1	03-2004	Wisnudel et al.	428/694.0ML
*	E	US-2005/0036440 A1	02-2005	Van Den Oetelaar, Ronald Joseph Antonius	369/275.5
*	F	US-2005/0163023 A1	07-2005	Van Den Oetelaar, Ronald Joseph Antonius	369/275.1
*	G	US-2006/0087955 A1	04-2006	Van Den Oetelaar, Ronald Joseph Antonius	369/275.1
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.